#5 KC, 7-24/02



**PATENT** 

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Shin-itsu TAKEHASHI et al.

Serial No.: 10/088,264

Filed: March 18, 2002

THIN FILM TRANSISTOR AND METHOD FOR FABRICATING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, D.C. 20231

Sír:

JUL 2 3 2002

Group Art Wait:

Examiner:

Pursuant to 37 C.F.R. §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached Form PTO-1449. Copies of each of the references listed on Form PTO-1449 are attached.

JP '834, JP '246, JP '552, JP '222, JP '403, JP '080, JP '691, JP '304, JP '366 and JP '221 are cited in the International Search Report bearing a mailing date of January 16, 2001, which was filed with the current application on March 18, 2002, and the U.S. PTO is directed thereto for a concise statement of possible relevance of the above-mentioned references.

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PLEASE ACCEPT THIS AS AUTHORIZATION TO DEBIT OR CREDIT FEES TO DEP. ACCT. 16-0331 PARKHURST & WENDEL JP '266 is of the family of US '164, JP '246 is of the family of US '802, JP '403 is of the family of US '304, JP '304 is of the family of US '701, and JP '221 is of the family of US '211, and copies of each of those patents are enclosed.

Euro Display '96, pp. 555-558, SID '96 Digest, pp. 25-28, and ASIA DISPLAY '95, pp. 335-337 are discussed on page 2 of the present specification.

The above information is presented so that the Patent and Trademark Office may, in the first instance, determine any materiality thereof to the claimed invention. See 37 C.F.R. 1.104(a) and 1.106(b) concerning the PTO duty to consider and use any such information. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that these references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

PARKHURST & WENDEL, L.L.P.

July 8, 2002

Date

Roger W. Parkhurst

Registration No. 25,177

RWP/jmz

Attorney Docket No.: OGOH:108
PARKHURST & WENDEL, L.L.P.

1421 Prince Street, Suite 210

Alexandria, Virginia 22314-2805

Telephone: (703) 739-0220

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Sheet 1 of 2	1,		`			w sain			
FORM PTO 1449 (modifie			ATTY DOCKET NO. SERIAL 10/088,2						
PATENT A	RTMENT OF COMMEI	ICE	APPLICANT Shin-itsu TAKEHASHI et al.						
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if thecessary)			FILING DATE March 18, 2002			GROUP			
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL	DOCUMENT NUMBER 240	MARK	NAME	CLASS		SUBCLASS	FILING DATE IF APPROPRIATE		
	6,140,164	10/31/2000	Zhang	438		163			
	6,127,211	10/03/2000	Hirao et al.	438		158			
	5,985,701	11/16/1999	Takei et al.	438		154			
	5,526,304	06/11/1996	Kawamura	365		154			
	5,476,802	12/19/1995	Yamazaki et al.	437		21			
			FOREIGN PATENT DOCUMENTS	s					
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS		SUBCLASS	TRANSLATION NO YES		
	03-148834	06/25/1991	Japan					Abstract	
	5-55246	03/05/1993	Japan				×		
•	05-082552	04/02/1993	Japan					Abstract	
•	06-112222	04/22/1994	Japan					Abstract	
	7-183403	07/21/1995	Japan				· x		
	08-032080	02/02/1996	Japan		_			Abstract	
	08-148691	06/07/1996	Japan					Abstract	
	9-298304	11/18/1997	Japan				x		
~	11-163366	06/18/1999	Japan					Abstract	
		OTHE	R DOCUMENT(S) (Including Author, Title, Date, F	Pertinent Pages	, Etc.)				
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 2	,											
FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. OGOH:108	SERIAL NO. 10/088,264								
			APPLICANT Shin-itsu TAKEHASHI et al.									
			FILING DATE March 18, 2002	GROUP								
U.S. PATENT DOCUMENTS												
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE						
61P												
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FOREIGN PATENT DOCUMENTS												
PADEMARKS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUBCLASS		TRANS	TRANSLATION NO YES					
	11-168221	06/22/1999	Japan			х						
	9-148266	06/06/1997	Japan			x						
	10-233511	09/02/1998	Japan				Abstract					
		OTHE	R DOCUMENT(S) (Including Author, Title, Date, I	Pertinent Pages, Etc.)								
	"Laser Crystallised Poly-Si Circuits for AMLCDs" Edwards, M.J., et al. ASIA DISPLAY '95, pp. 335-337.											
	"New Poly-Si TFT Structure for OFF-Current Reduction" Bae, B.S., et al. SID '96 DIGEST, pp. 25-28.											
	AMLCDs and Electronics on Polymer Substrates" Young, N.D., et al. Euro Display '96, pp. 555-558.											
	"Gate-Overlapped Lightly Doped Drain Poly-Si Thin-Film Transistors for Large Area-AMLCD" Choi, Kwon-Young, et al. IEEE Transaction on											
o Electronic Devices, Vol. 45, No. 6, June 1998, pp. 1272-1279.												
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.